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Application/Control No.	Applicant(s)/Patent under Reexamination
10/659,974	KRYZAK ET AL.
Examiner	Art Unit
Ted M. Wang	2611

	SEARCHED					
Class	Subclass	Date	Examiner			
375	219, 220, 222	12/6/2007	τw			
370	535	12/6/2007	TW			
455	73, 88	12/6/2007	TW			
455	507	12/6/2007	TW			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
375	219, 220	12/6/2007	TW		
375	222	12/6/2007	TW		
370	535	12/6/2007	TW		
455/73, 88, 507		12/6/2007	TW		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	12/6/2007	TW			
ODP- searched and reviewed.	12/6/2007	TW∙			
Inventor search - (Kryzak with (Joseph or Neil)) or (Hoelscher with Aaron) or (Rock with Thomas)	12/6/2007	τw			
IEEE- Author - Kryzak J. and Hoelscher A. and Rock T. and Kryzak J. N.	12/6/2007	TW			
IEEExplor - Advance search - Bond* (code or sequence) and transceiver and master and slave and detect and delay	12/6/2007	TW			